Band alignment in CdS-α-Te van der Waals heterostructures for photocatalytic applications: Influence of biaxial strain and electric field

G. Tejaswini^a, Anjana E Sudheer^a, M. Vallinayagam^{b,c}, M. Posselt^c, M. Zschornak^{b,c}, S Maniprakash^a, and D. Murali^a*

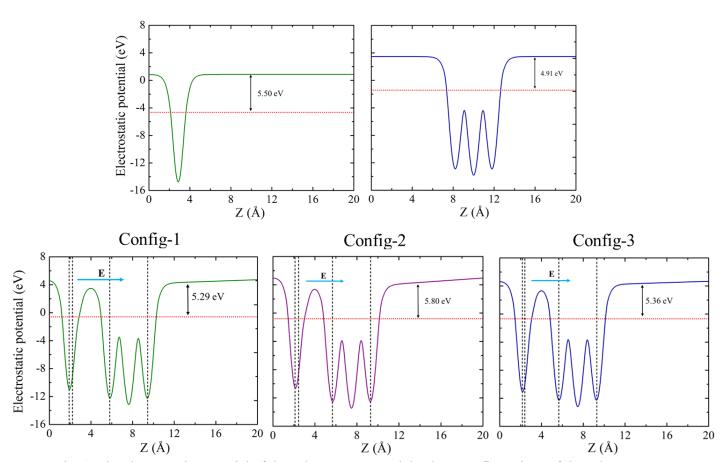
^a Indian Institute of Information Technology Design and Manufacturing, Kurnool, India.

E-mail: dmurali@iiitk.ac.in

^b IEP,TU Bergakademie Freiberg, 09599 Freiberg, Germany

^c Fakultät Maschinenbau/Energietechnik/Physik, Hochschule fur Technik und Wirtschaft 01069 Dresden, Germany

^d Helmholtz-Zentrum Dresden-Rossendorf, Institute of Ion Beam Physics and Materials Research,01328 Dresden, Germany

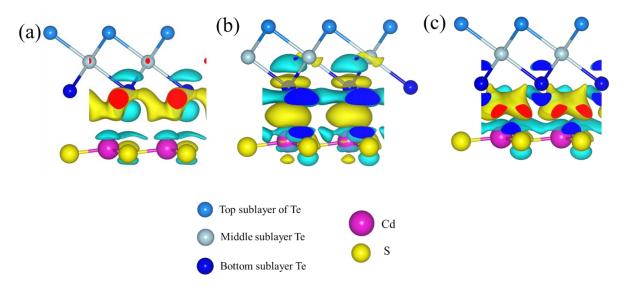


Supplementary Information

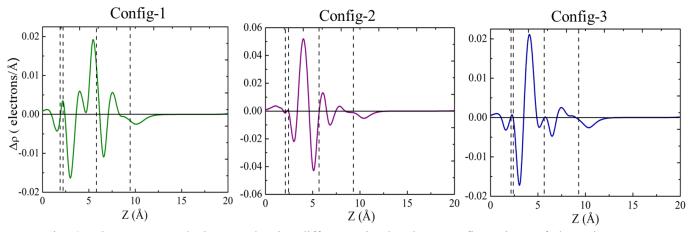
SFig. 1: The electrostatic potential of the CdS, α -Te SLs and the three configurations of the CdS- α -Te heterostructure. The vertical dashed lines represent the boundaries of the CdS (left) and α -Te (right) layers. The light blue arrow denotes the direction of the built-in electric field E. The red dotted line represents the Fermi-level. The results presented here are within the GGA approximation.

Structure	Vacuum level (eV)	Work function (eV)
CdS	0.86	5.50
α-Te	3.44	4.91
Config-1	4.71	5.29
Config-2	4.98	5.80
Config-3	4.68	5.36

STable 1: Vacuum level and work functions of CdS and α -Te SLs and CdS- α -Te heterostructure.



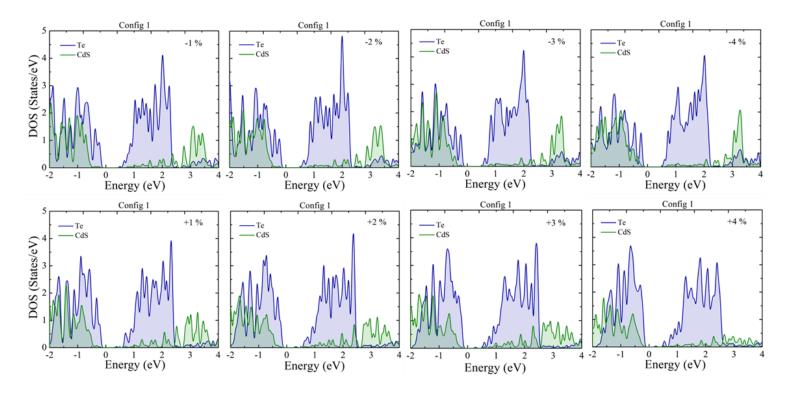
SFig. 2: Differential electron density representation in (a) config-1, (b) config-2 and (c) config-3 of the CdS- α -Te heterostructure with isosurface level 0.0002 e/Å³. The yellow and cyan colored regions around the atoms represents the electron accumulation and depletion respectively. Note, that the red and dark blue areas solely denote cross-sections of yellow and cyan regions with the plane of the picture.

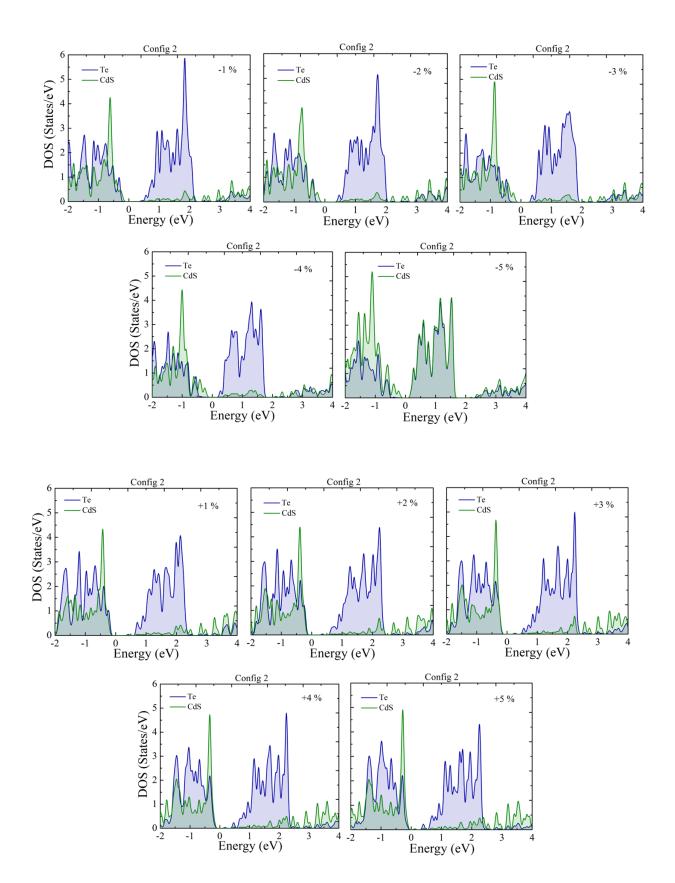


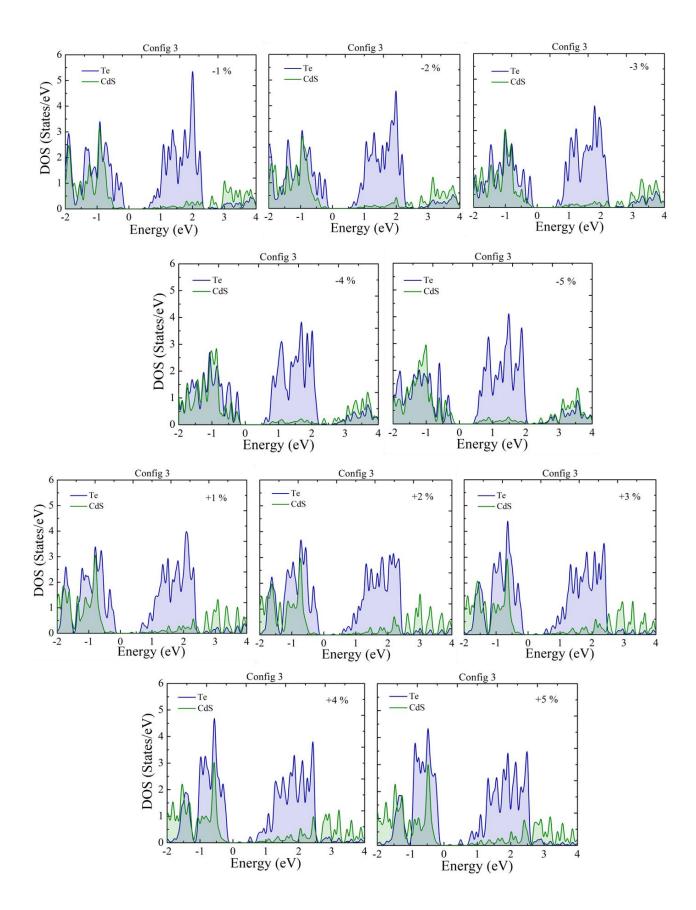
SFig. 3: Planar averaged electron density difference in the three configurations of the CdS- α Te heterostructure. Vertical dashed lines mark the CdS and α -Te regions. The positive and negative values represent the electron accumulation and depletion respectively.

STable 3: Interlayer distance variation with reference to applied biaxial strain in the three configurations of the CdS- α -Te heterostructure.

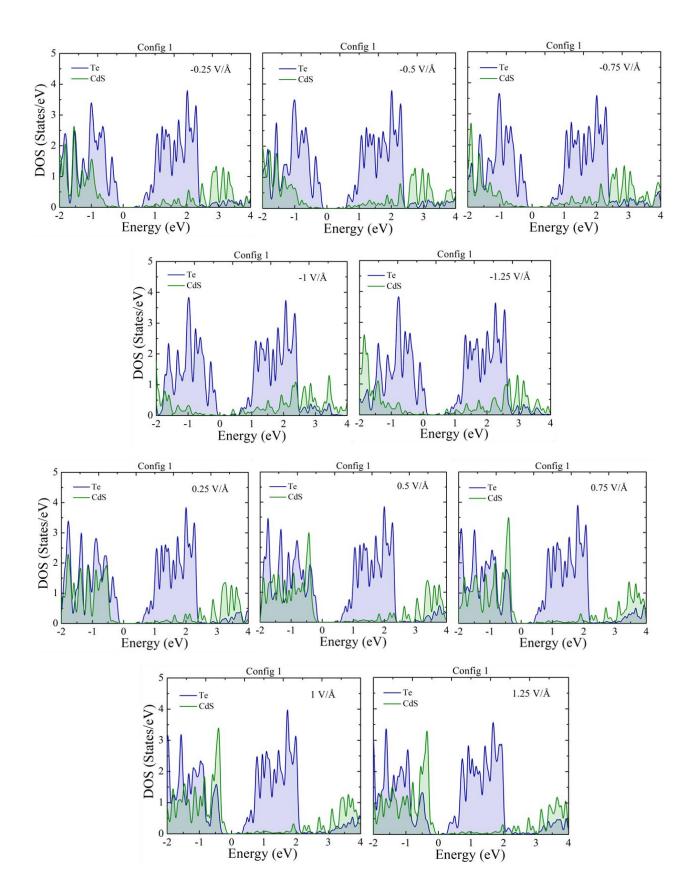
Strain (%)	Interlayer distance (Å)		
	Config-1	Config-2	Config-3
-5	-	3.00	3.10
-4	3.43	3.08	3.13
-3	3.47	3.14	3.16
-2	3.51	3.19	3.18
-1	3.55	3.23	3.21
0	3.59	3.23	3.25
1	3.62	3.27	3.24
2	3.65	3.26	3.25
3	3.67	3.25	3.24
4	3.69	3.23	3.22
5	-	3.20	3.20

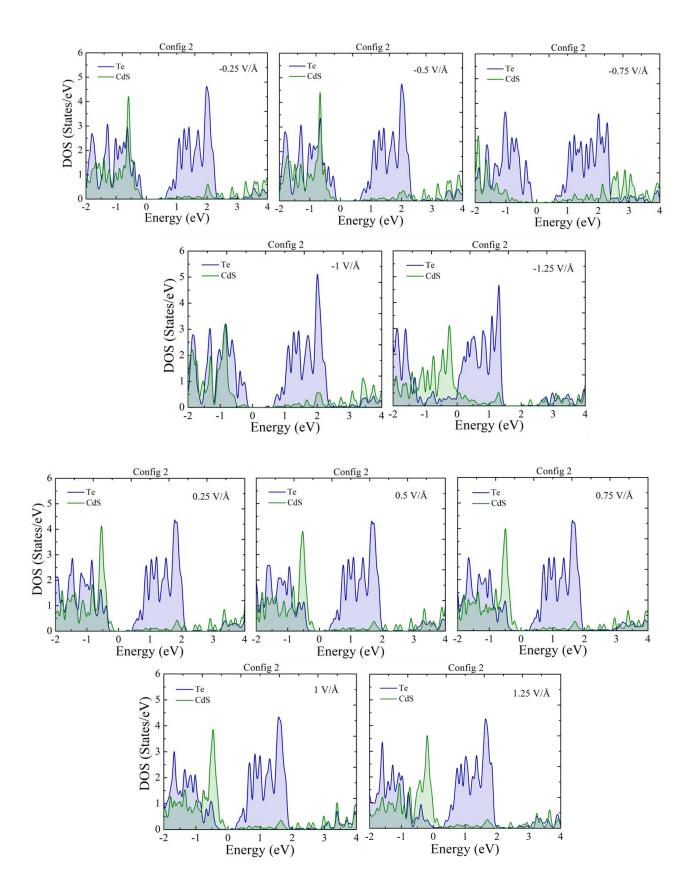


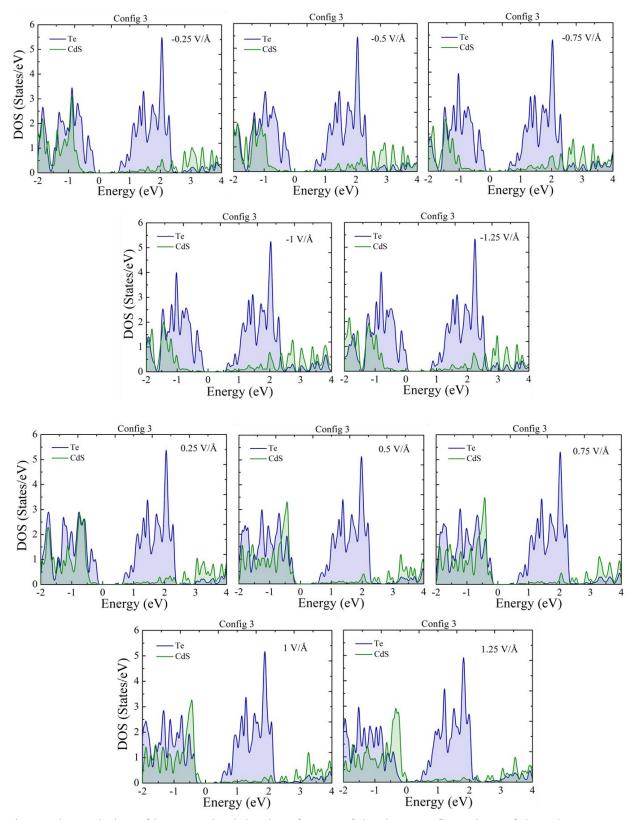




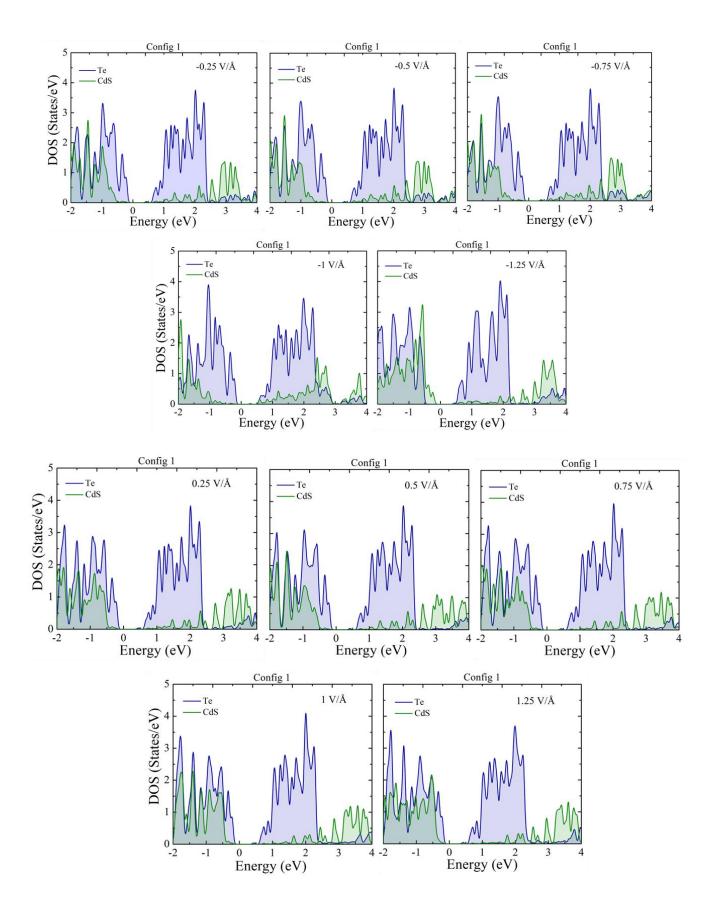
SFig 4: The evolution of layer resolved density (LDOS) of states of the three configurations of the CdS- α -Te heterostructure with respect to applied biaxial strain. The negative and positive strain values represent the compression and tension respectively. The Fermi-level is set to zero.

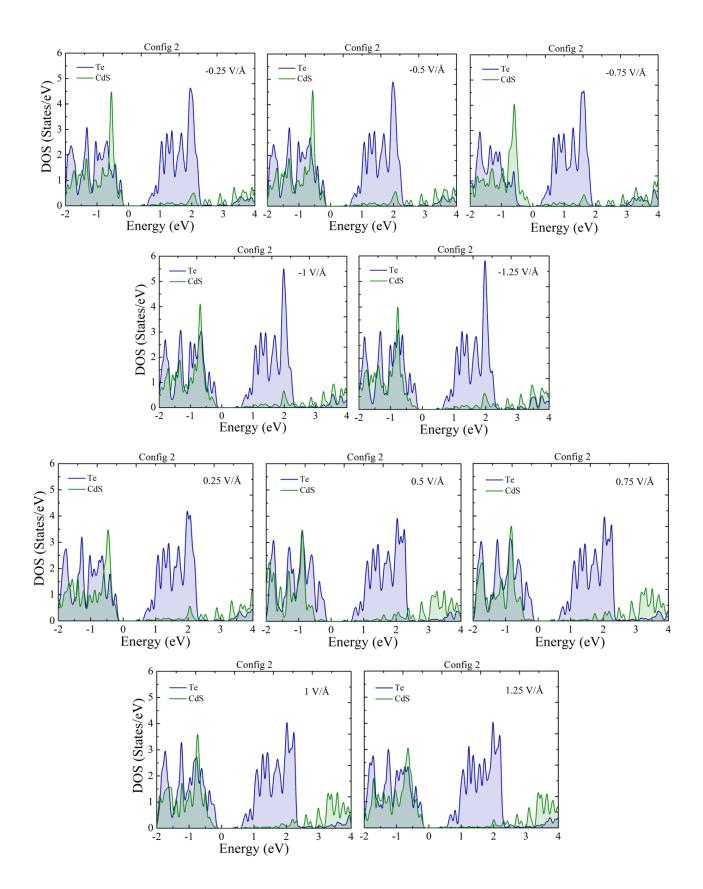


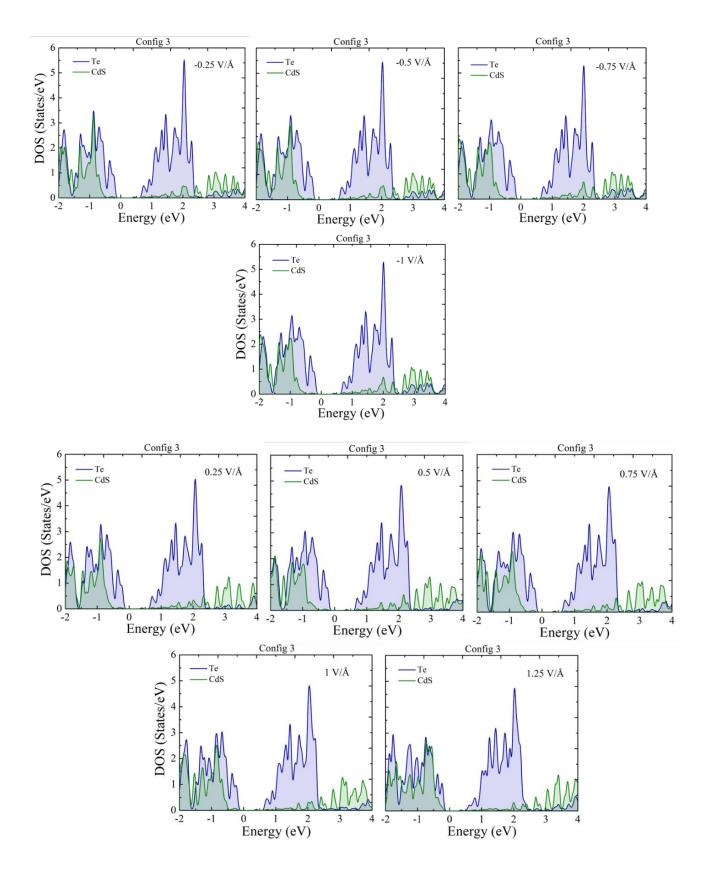




SFig. 5: The evolution of layer resolved density of states of the three configurations of the CdS- α -Te interface with respect to applied electric field. The negative and positive electric field values represent the direction of the fields pointing along negative and positive z-axis. respectively. The Fermi-level is set to zero. These are the results when the ionic relaxation is not performed.







SFig. 6: The evolution of layer resolved density of states of the CdS- α -Te heterostructure with respect to applied electric field. The negative and positive electric field values represent the direction of the fields pointing along negative and positive z-axis. respectively. The Fermi-level is set to zero. These are the results when the ionic relaxation is performed.